

## N-channel 600 V, 0.037 $\Omega$ typ., 66 A MDmesh™ DM2 Power MOSFET in a TO-247 long leads package

Datasheet - preliminary data

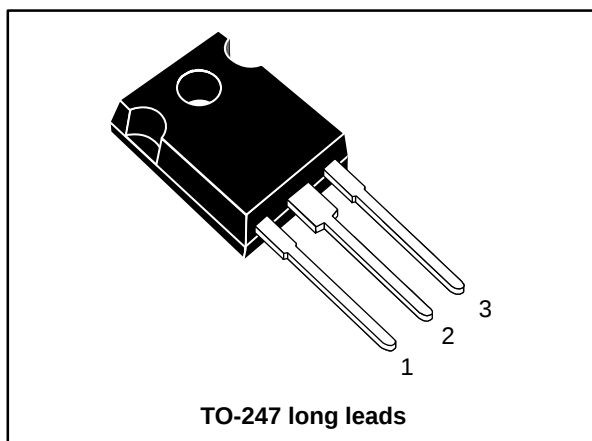
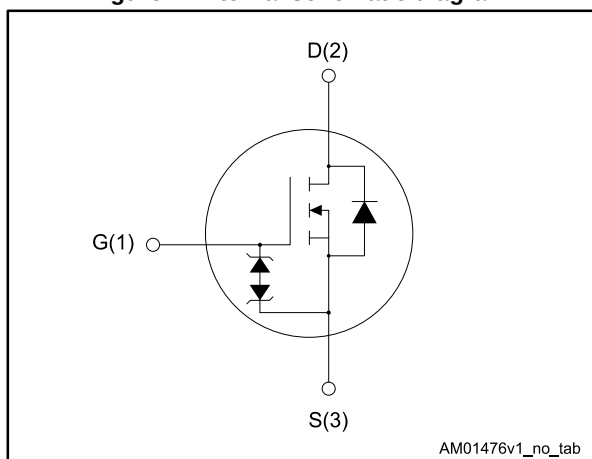


Figure 1: Internal schematic diagram



### Features

| Order code   | $V_{DS}$ | $R_{DS(on)}$<br>max. | $I_D$ | $P_{TOT}$ |
|--------------|----------|----------------------|-------|-----------|
| STWA70N60DM2 | 600 V    | 0.042 $\Omega$       | 66 A  | 446 W     |

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- Low on-resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

### Applications

- Switching applications

### Description

This high voltage N-channel Power MOSFET is part of the MDmesh™ DM2 fast recovery diode series. It offers very low recovery charge ( $Q_{rr}$ ) and time ( $t_{rr}$ ) combined with low  $R_{DS(on)}$ , rendering it suitable for the most demanding high efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

Table 1: Device summary

| Order code   | Marking  | Package           | Packing |
|--------------|----------|-------------------|---------|
| STWA70N60DM2 | 70N60DM2 | TO-247 long leads | Tube    |

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## Contents

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# 1 Electrical ratings

Table 2: Absolute maximum ratings

| Symbol         | Parameter                                                              | Value      | Unit               |
|----------------|------------------------------------------------------------------------|------------|--------------------|
| $V_{GS}$       | Gate-source voltage                                                    | $\pm 25$   | V                  |
| $I_D$          | Drain current (continuous) at $T_{case} = 25\text{ }^{\circ}\text{C}$  | 66         | A                  |
|                | Drain current (continuous) at $T_{case} = 100\text{ }^{\circ}\text{C}$ | 42         |                    |
| $I_{DM}^{(1)}$ | Drain current (pulsed)                                                 | 264        | A                  |
| $P_{TOT}$      | Total dissipation at $T_{case} = 25\text{ }^{\circ}\text{C}$           | 446        | W                  |
| $dv/dt^{(2)}$  | Peak diode recovery voltage slope                                      | 50         | V/ns               |
| $dv/dt^{(3)}$  | MOSFET $dv/dt$ ruggedness                                              | 50         |                    |
| $T_{stg}$      | Storage temperature                                                    | -55 to 150 | $^{\circ}\text{C}$ |
| $T_j$          | Operating junction temperature                                         |            |                    |

**Notes:**

(1) Pulse width is limited by safe operating area.

(2)  $I_{SD} \leq 66\text{ A}$ ,  $di/dt = 900\text{ A}/\mu\text{s}$ ;  $V_{DS}$  peak  $< V_{(BR)DSS}$ ,  $V_{DD} = 400\text{ V}$ .

(3)  $V_{DS} \leq 480\text{ V}$ .

Table 3: Thermal data

| Symbol         | Parameter                           | Value | Unit                        |
|----------------|-------------------------------------|-------|-----------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case    | 0.28  | $^{\circ}\text{C}/\text{W}$ |
| $R_{thj-amb}$  | Thermal resistance junction-ambient | 50    |                             |

Table 4: Avalanche characteristics

| Symbol   | Parameter                                                                                                              | Value | Unit |
|----------|------------------------------------------------------------------------------------------------------------------------|-------|------|
| $I_{AR}$ | Avalanche current, repetitive or not repetitive (Pulse width limited by $T_{jmax}$ )                                   | 10    | A    |
| $E_{AR}$ | Single pulse avalanche energy (starting $T_j = 25\text{ }^{\circ}\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ ) | 1500  | mJ   |

## 2 Electrical characteristics

( $T_{\text{case}} = 25\text{ }^{\circ}\text{C}$  unless otherwise specified)

**Table 5: Static**

| Symbol                      | Parameter                         | Test conditions                                                                                                    | Min. | Typ.  | Max.    | Unit          |
|-----------------------------|-----------------------------------|--------------------------------------------------------------------------------------------------------------------|------|-------|---------|---------------|
| $V_{(\text{BR})\text{DSS}}$ | Drain-source breakdown voltage    | $V_{\text{GS}} = 0\text{ V}$ , $I_{\text{D}} = 1\text{ mA}$                                                        | 600  |       |         | V             |
| $I_{\text{DSS}}$            | Zero gate voltage drain current   | $V_{\text{GS}} = 0\text{ V}$ , $V_{\text{DS}} = 600\text{ V}$                                                      |      |       | 10      | $\mu\text{A}$ |
|                             |                                   | $V_{\text{GS}} = 0\text{ V}$ , $V_{\text{DS}} = 600\text{ V}$ ,<br>$T_{\text{case}} = 125\text{ }^{\circ}\text{C}$ |      |       | 100     |               |
| $I_{\text{GSS}}$            | Gate-body leakage current         | $V_{\text{DS}} = 0\text{ V}$ , $V_{\text{GS}} = \pm 25\text{ V}$                                                   |      |       | $\pm 5$ | $\mu\text{A}$ |
| $V_{\text{GS(th)}}$         | Gate threshold voltage            | $V_{\text{DS}} = V_{\text{GS}}$ , $I_{\text{D}} = 250\text{ }\mu\text{A}$                                          | 3    | 4     | 5       | V             |
| $R_{\text{DS(on)}}$         | Static drain-source on-resistance | $V_{\text{GS}} = 10\text{ V}$ , $I_{\text{D}} = 33\text{ A}$                                                       |      | 0.037 | 0.042   | $\Omega$      |

**Table 6: Dynamic**

| Symbol                   | Parameter                     | Test conditions                                                                                                                                               | Min. | Typ. | Max. | Unit     |
|--------------------------|-------------------------------|---------------------------------------------------------------------------------------------------------------------------------------------------------------|------|------|------|----------|
| $C_{\text{iss}}$         | Input capacitance             | $V_{\text{DS}} = 100\text{ V}$ , $f = 1\text{ MHz}$ ,<br>$I_{\text{D}} = 0\text{ A}$                                                                          | -    | 5508 | -    | pF       |
| $C_{\text{oss}}$         | Output capacitance            |                                                                                                                                                               | -    | 241  | -    |          |
| $C_{\text{rss}}$         | Reverse transfer capacitance  |                                                                                                                                                               | -    | 2.8  | -    |          |
| $C_{\text{oss eq. (1)}}$ | Equivalent output capacitance | $V_{\text{DS}} = 0\text{ to }480\text{ V}$ , $V_{\text{GS}} = 0\text{ V}$                                                                                     | -    | 470  | -    | pF       |
| $R_{\text{G}}$           | Intrinsic gate resistance     | $f = 1\text{ MHz}$ , $I_{\text{D}} = 0\text{ A}$                                                                                                              | -    | 2    | -    | $\Omega$ |
| $Q_{\text{g}}$           | Total gate charge             | $V_{\text{DD}} = 480\text{ V}$ , $I_{\text{D}} = 66\text{ A}$ ,<br>$V_{\text{GS}} = 10\text{ V}$ (see <a href="#">Figure 15: "Gate charge test circuit"</a> ) | -    | 120  | -    | nC       |
| $Q_{\text{gs}}$          | Gate-source charge            |                                                                                                                                                               | -    | 26   | -    |          |
| $Q_{\text{gd}}$          | Gate-drain charge             |                                                                                                                                                               | -    | 60   | -    |          |

**Notes:**

(1)  $C_{\text{oss eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{\text{oss}}$  when  $V_{\text{DS}}$  increases from 0 to 80%  $V_{\text{DSS}}$ .

**Table 7: Switching times**

| Symbol              | Parameter           | Test conditions                                                                                                                                                                                                             | Min. | Typ. | Max. | Unit |
|---------------------|---------------------|-----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|------|------|------|------|
| $t_{\text{d(on)}}$  | Turn-on delay time  | $V_{\text{DD}} = 300\text{ V}$ , $I_{\text{D}} = 33\text{ A}$<br>$R_{\text{G}} = 4.7\text{ }\Omega$ , $V_{\text{GS}} = 10\text{ V}$ (see <a href="#">Figure 14: "Switching times test circuit for resistive load"</a> and ) | -    | 32   | -    | ns   |
| $t_{\text{r}}$      | Rise time           |                                                                                                                                                                                                                             | -    | 67   | -    |      |
| $t_{\text{d(off)}}$ | Turn-off delay time |                                                                                                                                                                                                                             | -    | 112  | -    |      |
| $t_{\text{f}}$      | Fall time           |                                                                                                                                                                                                                             | -    | 10.4 | -    |      |

Table 8: Source-drain diode

| Symbol          | Parameter                     | Test conditions                                                                                                                                                                                                                       | Min. | Typ. | Max. | Unit          |
|-----------------|-------------------------------|---------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|------|------|------|---------------|
| $I_{SD}$        | Source-drain current          |                                                                                                                                                                                                                                       | -    |      | 66   | A             |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) |                                                                                                                                                                                                                                       | -    |      | 264  | A             |
| $V_{SD}^{(2)}$  | Forward on voltage            | $V_{GS} = 0\text{ V}$ , $I_{SD} = 66\text{ A}$                                                                                                                                                                                        | -    |      | 1.6  | V             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 66\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD} = 60\text{ V}$ (see <a href="#">Figure 16</a> :<br>"Test circuit for inductive load switching and diode recovery times")                                     | -    | 150  |      | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                                                                                                                                       | -    | 0.72 |      | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      |                                                                                                                                                                                                                                       | -    | 9.6  |      | A             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 66\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD} = 60\text{ V}$ , $T_j = 150\text{ }^\circ\text{C}$ (see<br><a href="#">Figure 16</a> : "Test circuit for inductive load switching and diode recovery times") | -    | 250  |      | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                                                                                                                                       | -    | 2.55 |      | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      |                                                                                                                                                                                                                                       | -    | 20.4 |      | A             |

**Notes:**

<sup>(1)</sup> Pulse width is limited by safe operating area.

<sup>(2)</sup> Pulse test: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

## 2.1 Electrical characteristics (curves)

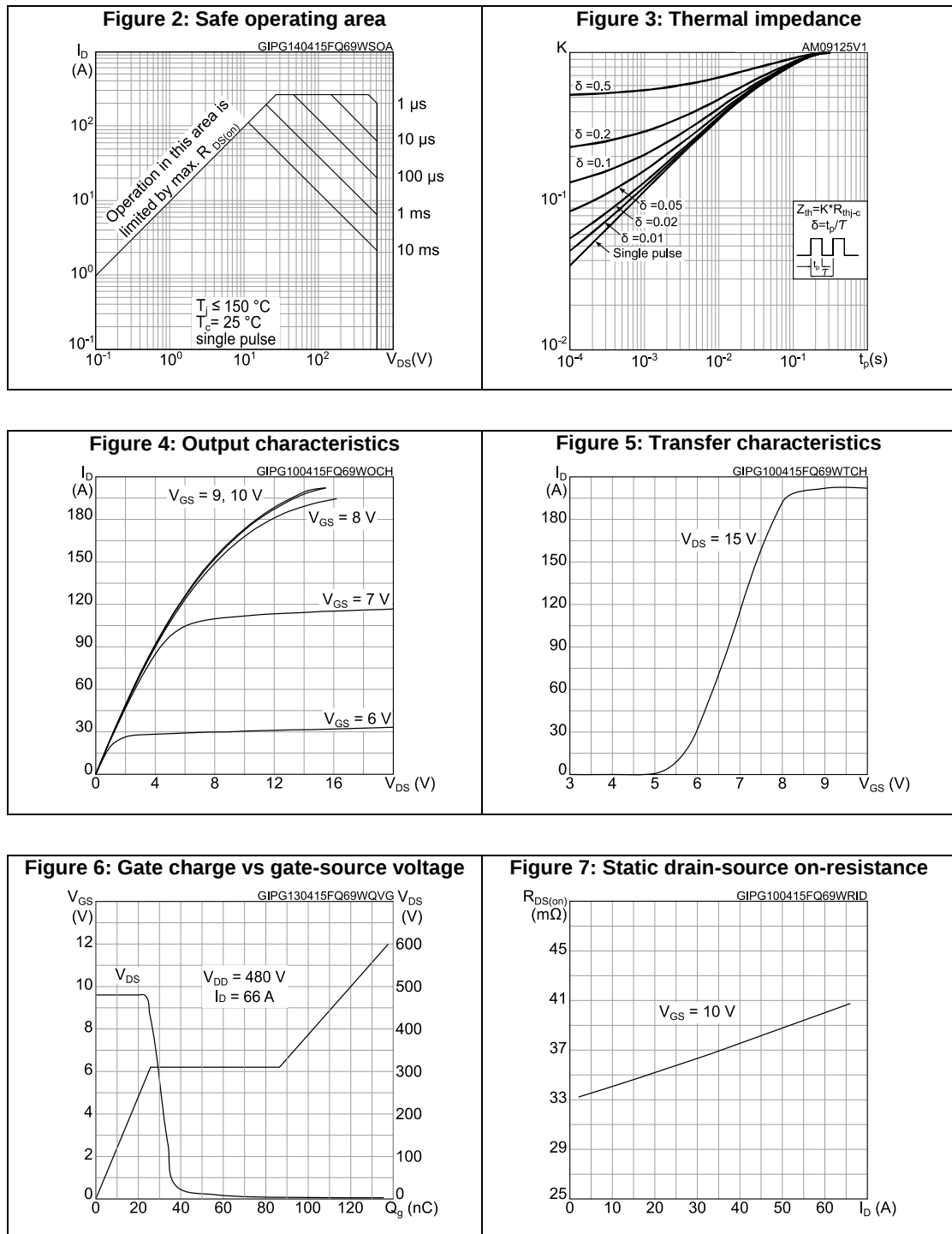


Figure 8: Capacitance variations

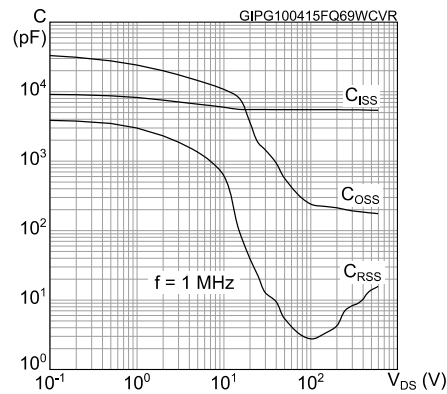


Figure 9: Normalized gate threshold voltage vs temperature

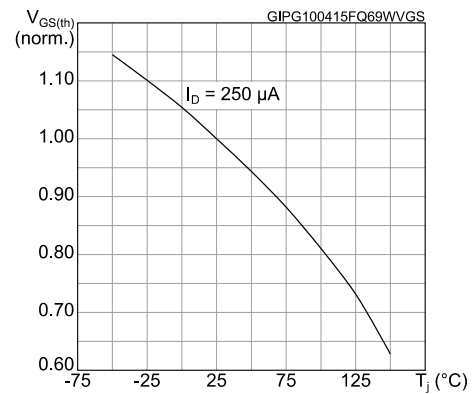


Figure 10: Normalized on-resistance vs temperature

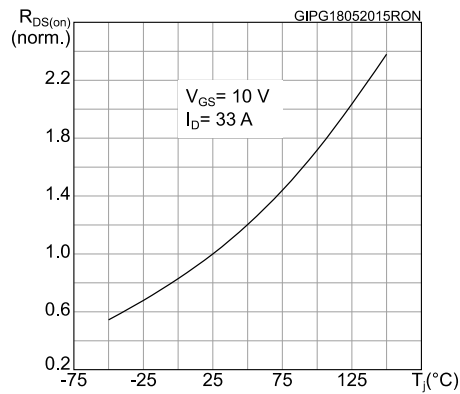


Figure 11: Normalized V(BR)DSS vs temperature

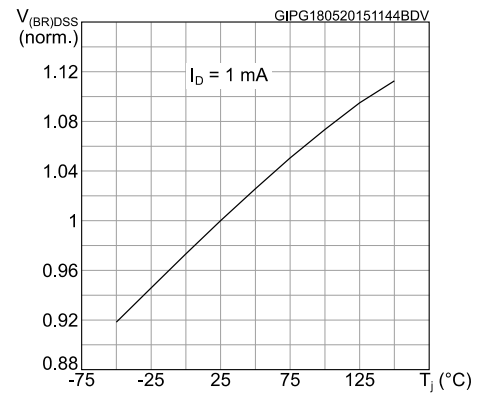


Figure 12: Output capacitance stored energy

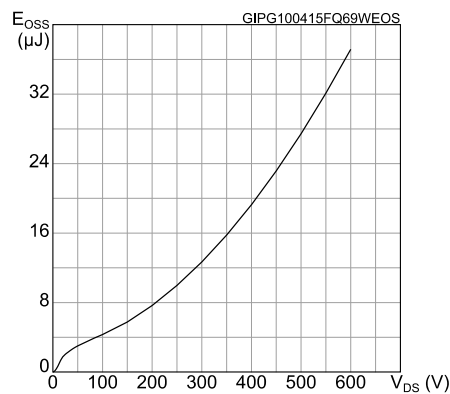
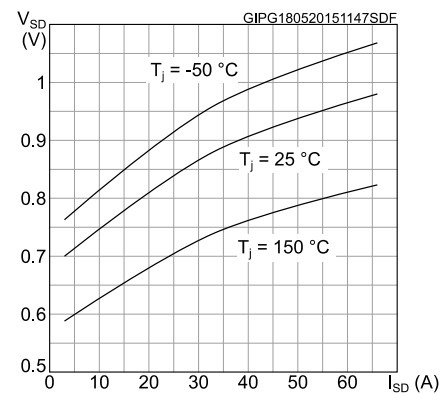


Figure 13: Source- drain diode forward characteristics



AM01468v1

AM01469v1

AM01470v1

AM01471v1

AM01472v1

AM01473v1

## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK® is an ST trademark.

### 4.1 TO-247 long leads package information

Figure 20: TO-247 long leads package outline

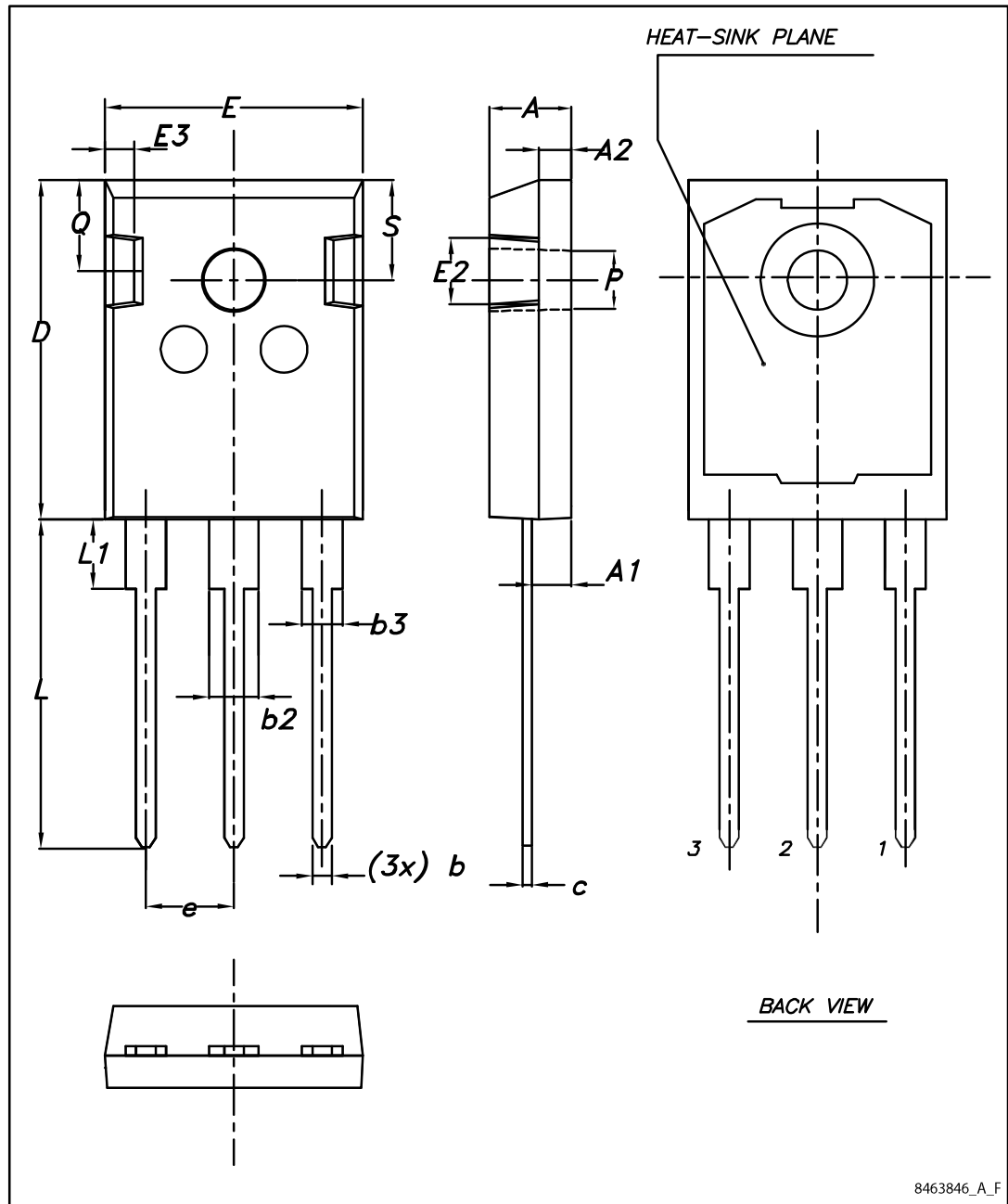


Table 9: TO-247 long leads package mechanical data

| Dim. | mm.   |       |       |
|------|-------|-------|-------|
|      | Min.  | Typ.  | Max.  |
| A    | 4.90  | 5.00  | 5.10  |
| A1   | 2.31  | 2.41  | 2.51  |
| A2   | 1.90  | 2.00  | 2.10  |
| b    | 1.16  |       | 1.26  |
| b2   |       |       | 3.25  |
| b3   |       |       | 2.25  |
| c    | 0.59  |       | 0.66  |
| D    | 20.90 | 21.00 | 21.10 |
| E    | 15.70 | 15.80 | 15.90 |
| E2   | 4.90  | 5.00  | 5.10  |
| E3   | 2.40  | 2.50  | 2.60  |
| e    | 5.34  | 5.44  | 5.54  |
| L    | 19.80 | 19.92 | 20.10 |
| L1   |       |       | 4.30  |
| P    | 3.50  | 3.60  | 3.70  |
| Q    | 5.60  |       | 6.00  |
| S    | 6.05  | 6.15  | 6.25  |

## 5 Revision history

Table 10: Document revision history

| Date        | Revision | Changes        |
|-------------|----------|----------------|
| 19-May-2015 | 1        | First release. |

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